Electronic Supplementary Material (ESI) for Materials Advances. This journal is © The Royal Society of Chemistry 2023

Electronic Supplementary Material (ESI) for Materials Advances.

This journal is  $\ensuremath{\mathbb{C}}$  The Rouyal Society of Chemistry 2023

## Supplementary Information

## Photo-enhanced Metal-assisted Chemical Etching of $\alpha$ -Gallium Oxide Grown by Halide Vapor-Phase Epitaxy on a Sapphire Substrate and its Applications

Woong Choi,<sup>a</sup> Dae-Woo Jeon,<sup>b</sup> Ji-Hyeon Park,<sup>b</sup> Dongryul Lee,<sup>c</sup> Soobeen Lee,<sup>a</sup> Kwang Hyeon Baik<sup>d</sup> and Jihyun Kim<sup>a, †</sup>

<sup>a</sup>Department of Chemical and Biological Engineering, Seoul National University, Seoul 08826, South Korea

<sup>b</sup>Korea Institute of Ceramic Engineering and Technology, Jinju 52851, South Korea

<sup>o</sup>Department of Chemical and Biological Engineering, Korea University, Seoul 02841, South Korea

<sup>d</sup>Department of Materials Science and Engineering, Hongik University, Jochiwon, Sejong 30016, South Korea

<sup>†</sup>Corresponding author: Jihyun Kim (jihyunkim@snu.ac.kr)



**Figure S1.** (a) Etch rate (E/R) of PE-MAC etch of  $\alpha$ -Ga<sub>2</sub>O<sub>3</sub> at 32 °C. (b) RMS roughness changes at 32 °C etching. (c) Etch rate (E/R) of PE-MAC etch of  $\alpha$ -Ga<sub>2</sub>O<sub>3</sub> at 45 °C. (d) RMS roughness changes in 45 °C etching. (e) Etch rate (E/R) of PE-MAC etch of  $\alpha$ -Ga<sub>2</sub>O<sub>3</sub> at 50 °C. (f) RMS roughness changes in 50 °C etching.



**Figure S2.** *I*–*V* characteristics of  $\alpha$ -Ga<sub>2</sub>O<sub>3</sub> PD under dark condition as well as 254 and 365 nm lights illuminations.